

Optimal design for accelerated degradation tests with stochastic model uncertainty

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- ◆ Model uncertainty in ADT planning.
- ◆ Bayesian model averaging method.
- ◆ Optimization problem.
- ◆ Illustrative example & sensitivity analysis.
- ◆ Conclusion & future work.

Literature Review

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- ▶ Why is Accelerated degradation testing ? – High reliability & Long lifespan VS Time constraint.
- ▶ How to design ADT plan ? – Target &

1. Total cost	1. Sample size allocation
2. Estimation precision of the lifetime	2. Inspection times
3. Etc.	3. Stress levels
	4. Etc.
- ▶ What is the model ADT data? Degradation
- ▶ How to quantify model uncertainty
Gamma process and inverse Gaussian process ?
- ▶ Are there any relevant researches on this topic ?

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Model uncertainty

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□ Stochastic process models for degradation modeling

- Wiener process (M1)
- Gamma process (M2)
- Inverse Gaussian process (M3)

Basic assumptions:

- $\forall t_2 > t_1 \geq s_2 > s_1$, $X(t)$ has independent increments, that is, $X(t_2) - X(t_1)$ and $X(s_2) - X(s_1)$ are independent.
- $\forall t \geq s > 0$, $X(t) - X(s)$ follows **certain distributions**, whose mean and variance are proportional to $\Lambda(t) - \Lambda(s)$.

where $\Lambda(t)$ is the time-scale transformation.

Model uncertainty

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- Unified stochastic process model $USP(a, b)$

$$E[X] = \mu\Lambda(t)$$

$$\text{Var}[X] = \sigma^2\Lambda(t)$$

Model	a	$b > 0$	PDF
M_1	$\mu\Lambda(t)$	$\sqrt{\sigma^2\Lambda(t)}$	$f_N(x a, b) = \frac{1}{\sqrt{2\pi}b} \exp\left[-\frac{(x-a)^2}{2b^2}\right]$
M_2	$\mu^2\Lambda(t)/\sigma^2$	σ^2/μ	$f_{Ga}(x a, b) = \frac{b^{-a}}{\Gamma(a)} x^{a-1} \exp\left(-\frac{x}{b}\right), x > 0$
M_3	$\mu\Lambda(t)$	$\mu^3\Lambda^2(t)/\sigma^2$	$f_{IG}(x a, b) = \sqrt{\frac{b}{2\pi x^3}} \exp\left[-\frac{b(x-a)^2}{2a^2x}\right], x > 0$

Model uncertainty

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□ Acceleration model

$$\mu_i = \exp(\alpha_0 + \alpha_1 s_i)$$

where $s_i \in [0,1]$ is the normalized accelerated stress level by

$$s_i = \begin{cases} \frac{1/s'_0 - 1/s'_i}{1/s'_0 - 1/s'_H} & \text{Arrhenius relation} \\ \frac{\ln s'_i - \ln s'_0}{\ln s'_H - \ln s'_0} & \text{Power law relation} \\ \frac{s'_i - s'_0}{s'_H - s'_0} & \text{Exponential relation} \end{cases}$$

The degradation rate at the use condition is

$$\mu_0 = \exp(\alpha_0).$$

where s'_0 and s'_H are the normal and highest stress levels, $i = 1, 2, \dots, K$.

Model uncertainty

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- **The p-th quantile lifetime at the use condition**

**The influence of
Model Uncertainty**

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$$t_p = \Lambda^{-1} \left[\frac{\beta}{4} \left(\alpha z_p + \sqrt{4 + \alpha^2 z_p^2} \right)^2 \right]$$

where z_p is the p-quantile of the standard normal distribution, and $\Lambda^{-1}(\cdot)$ is the inverse function of $\Lambda(\cdot)$.

Based on the asymptotically normal distribution, the asymptotic variance of t_p can be given as

$$Avar(t_p) = (\nabla t_p)' I^{-1}(\theta) \nabla t_p$$

where $I(\theta)$ is the expected Fisher information matrix.

Bayesian model averaging (BMA)

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□ Uncertainty quantification

Considered that Δ is the quantity of interest, i.e. t_p at the use condition, its posterior distribution given data D is

$$f(\Delta|D) = \sum_{c=1}^C f(\Delta|M_c, D)Pr\{M_c|D\}$$

where $f(\Delta|M_c, D)$ is the posterior density of Δ assuming that M_c is the true model, $Pr\{M_c|D\}$ is the posterior probability of model M_c .

$$Pr\{M_c|D\} \propto f(D|M_c)Pr\{M_c\}$$

where $Pr(M_c)$ is the prior probability of model M_c , $f(D|M_c)$ is the integrated likelihood of model M_c

$$f(D|M_c) = \int f(D|\boldsymbol{\theta}_c, M_c) f(\boldsymbol{\theta}_c|M_c)$$

where $f(D|\boldsymbol{\theta}_c, M_c)$ is the likelihood function under model M_c .

Bayesian model averaging (BMA)

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□ Uncertainty quantification

For Δ , its posterior mean is

$$E(\Delta|D) = \sum_{c=1}^C \hat{\Delta}_c \Pr\{M_c|D\}$$

and its variance is



$$Var(\Delta|D) = \sum_{c=1}^C (Var(\Delta|M_c, D) + \hat{\Delta}_c) \Pr\{M_c|D\} - E(\Delta|D)^2$$

where $\hat{\Delta}_c = E(\Delta|M_c, D)$.

Optimization problem

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Single model

Minimize $Avar(\hat{t}_p)$

subject to $0 \leq s_i \leq 1, s_{i-1} \leq s_i, i \in [1, K]$

$$\sum_{i=1}^K n_i = N, n_i \leq n_{i-1}, i \in [2, K]$$

$$\sum_{i=1}^K m_i = M, m_i \leq m_{i-1}$$

n_i and $m_i \in N^+$

Multiple models

Minimize $Var[\hat{t}_p|D]$

subject to $0 \leq s_i \leq 1, s_{i-1} \leq s_i, i \in [1, K]$

$$\sum_{i=1}^K n_i = N, n_i \leq n_{i-1}, i \in [2, K]$$

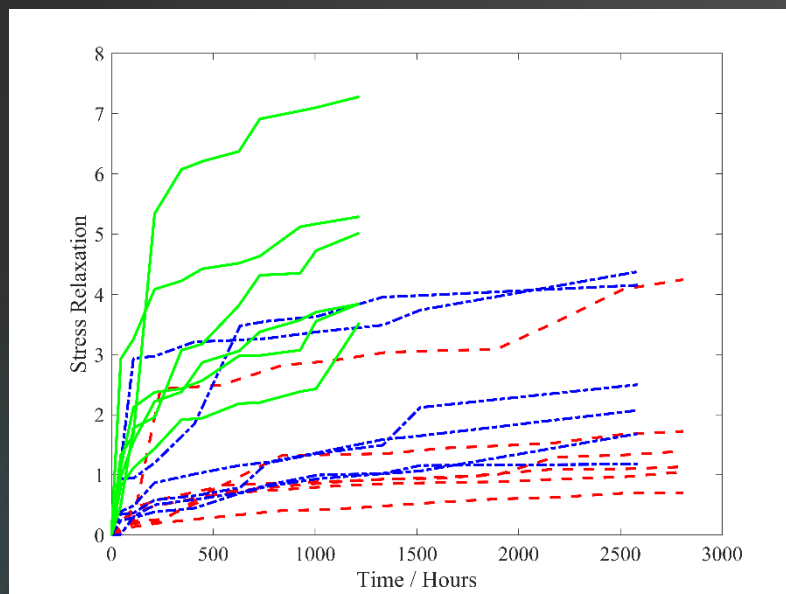
$$\sum_{i=1}^K m_i = M, m_i \leq m_{i-1}$$

n_i and $m_i \in N^+$

Illustrative example

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Stress relaxation CSADT data

Contents	Values
Accelerated stresses	65, 85, 100°C
Normal condition	40°C
Failure threshold	30%

Illustrative example

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□ Model selection with L_{max} value

Table 2: Parameter estimation for single model.

Models	Acceleration		Degradation		l_{max}
	α_0	α_1	σ	γ	
M_1	-3.4857	2.8951	0.4222	0.2997	-74.6
M_2	-2.9438	1.0417	0.1922	0.4381	55.1
M_3	-3.6858	1.2253	0.2606	0.5181	54.8

- this process maybe ignored in real applications with the assumption of the degradation model, or
- this selection maybe inappropriate for designing ADT plans without the consideration of model uncertainty.

Illustrative example

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□ Model comparison for the 2-level CSADT plan

Table 3: Optimal plan for 2-level CSADT.

Models	Samples		Inspection		Stress		$std(\hat{t}_p)$
	n_1	n_2	m_1	m_2	s_1	s_2	
M_1	8	2	96	4	0.59	1	3.32e9
M_2	7	3	84	16	0.59	1	7.44e5
M_3	5	5	67	33	0.73	1	2.54e5
<i>BMA</i>	7	3	82	18	0.61	1	7.16e5

Assumptions:

- ✓ $N = 10$ samples
- ✓ $M = 100$ inspection
- ✓ Time interval 24 hours
- ✓ $p = 0.1$

$$Pr(M_1 | D) = 0$$

$$Pr(M_2 | D) = 0.5628$$

&

$$Pr(M_3 | D) = 0.4372$$

- the optimal second stress level is the same for three candidate model ($s_2 = 1$, i.e. 100°C).
- the sample allocations, inspection times and the first stress level are different with different choice of the degradation model.
- M_2 is treated as the most suitable model from Table 2 but without the highest prediction precision.

Sensitivity analysis

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□ Variation of parameters

Setting true values as $\alpha_0 = 2$, $\alpha_1 = 1.5$, $\sigma = 0.5$, $\gamma = 0.4$ and the variations into three levels, i.e. +10%, 0, -10%. $Pr(Mc | D) = 1/3$.

Table 4: Sensitivity analysis of the variation of parameters on the optimal 2-level CSADT plan.

ϵ_1	ϵ_2	ϵ_3	ϵ_4	n_1	n_2	m_1	m_2	s_1	s_2	$std(\hat{t}_p)$
+10%	+10%	+10%	+10%	7	3	80	20	0.46	1	7.71e4
+10%	0	0	0	7	3	84	16	0.45	1	3.59e5
+10%	-10%	-10%	-10%	8	2	88	12	0.41	1	2.22e6
0	10%	-10%	0	7	3	81	19	0.48	1	1.90e5
0	0	+10%	-10%	7	3	85	15	0.46	1	1.06e6
0	-10%	0	10%	7	3	82	18	0.40	1	5.11e4
-10%	+10%	0	-10%	7	3	82	18	0.50	1	5.41e5
-10%	0	-10%	+10%	7	3	79	21	0.42	1	2.72e4
-10%	-10%	+10%	0	7	3	83	17	0.42	1	1.16e5

Sensitivity analysis

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□ Variation of model posterior probabilities

Setting true values as $\alpha_0 = 2$, $\alpha_1 = 1.5$, $\sigma = 0.5$, $\gamma = 0.4$
and the variations into three levels, i.e. +10%, 0, -10%,

Table 5: Sensitivity analysis of the variation of model posterior probabilities on the optimal 2-level CSADT plan.

$Pr(M_1 D)$	$Pr(M_2 D)$	$Pr(M_3 D)$	n_1	n_2	m_1	m_2	s_1	s_2	$std(\hat{t}_p)$
1/6	1/3	1/2	6	4	75	25	0.49	1	1.86e5
1/6	1/2	1/3	7	3	79	21	0.51	1	1.90e5
1/3	1/6	1/2	7	3	83	17	0.45	1	1.97e5
1/3	1/2	1/6	7	3	83	17	0.45	1	2.03e5
1/2	1/6	1/3	8	2	88	12	0.39	1	2.07e5
1/2	1/3	1/6	8	2	88	12	0.39	1	2.10e5

Summary

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- The BMA method is introduced to analyze the problem of stochastic model uncertainty on designing the optimal ADT plan.
- The simulated stress relaxation CSADT data shows that each stochastic degradation model can produce different optimal plan and prediction precision.
- The sensitivity study shows that the optimal plan is less sensitive to the variation of parameters but to model posterior probabilities, while that for the prediction precision is reverse.

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Future Work

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- The study of the random effects due to the variation of the tested samples
- Maybe the measurement error
- Compative study with reference model

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